


<b>Search Notes</b>  	<b>Application/Control No.</b>  10597971	<b>Applicant(s)/Patent Under Reexamination</b>  VAN DE KERKHOF, LEON MARIA
	<b>Examiner</b>  HAI PHAN	<b>Art Unit</b>  2614

SEARCHED			
Class	Subclass	Date	Examiner
381	23, 17	11/17/09	HP
704	500, 501	11/17/09	HP

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS search	11/17/2009	HP
EAST Search	11/17/2009	HP
Inventor Search	11/17/2009	HP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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